

**YGMOS Technology Crop.**

30V N-Channel Enhancement-Mode MOSFET    30V N 沟道增强型 MOS 管

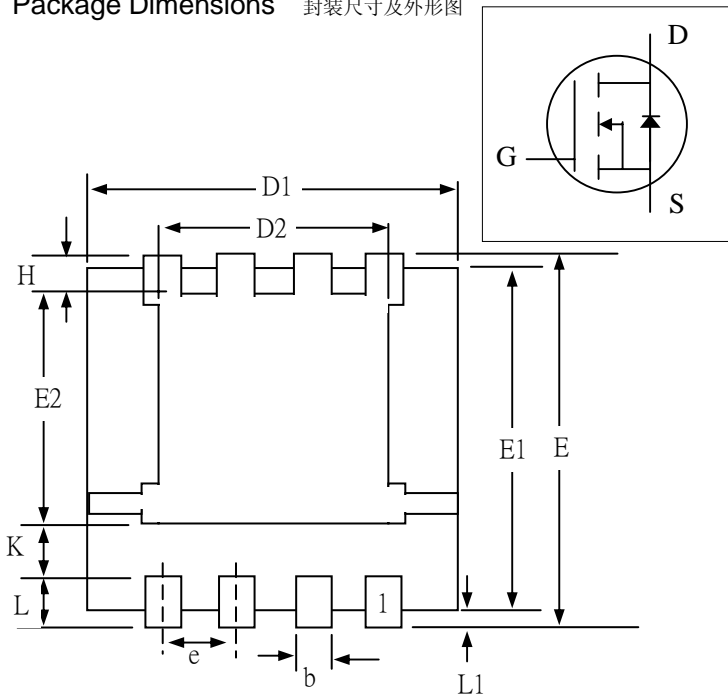
 **$V_{DS} = 30V$** 
 **$R_{DS(ON)}, V_{GS} @ 10V, I_{ds} @ 25A = 6m\Omega$** 
 **$R_{DS(ON)}, V_{GS} @ 4.5V, I_{ds} @ 25A = 10m\Omega$** 
**Features 特性**

Advanced trench process technology    高级的加工技术

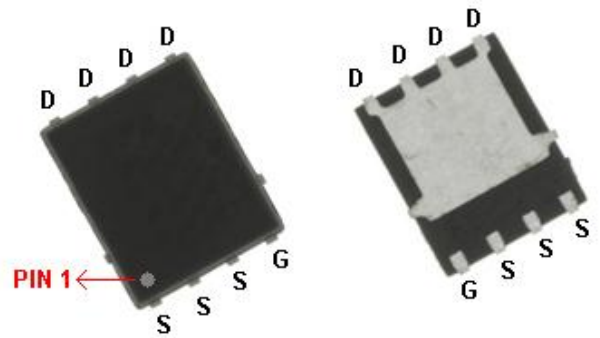
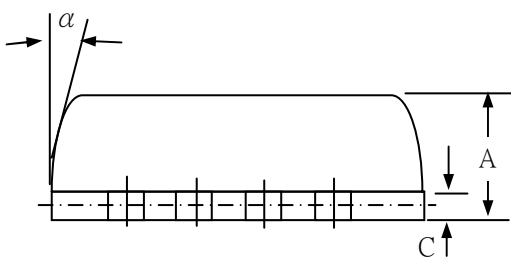
High Density Cell Design For Ultra Low On-Resistance    极低的导通电阻高密度的单元设计

**PDFN5\*6**

Package Dimensions    封装尺寸及外形图



BACKSIDE VIEW



Bottom View

Top View

SYMBOLS	Millimeters		
	MIN	NOM	MAX
A	0.90	1.10	1.30
b	0.33	0.41	0.51
C	0.15	—	—
D1	4.80	4.90	5.10
D2	—	—	4.40
E	5.80	6.00	6.20
E1 (Ref.)	5.60	5.75	5.90
E2 (Ref.)	3.30	3.55	3.80
e	1.27 BSC		
H	—	—	0.90
K (Ref.)	0.70	—	—
L	0.35	0.55	0.75
L1	—	—	0.20
$\alpha$	0°	—	12°

**Maximum Ratings and Thermal Characteristics (TA = 25°C unless otherwise noted)    25°C 极限参数和热特性**

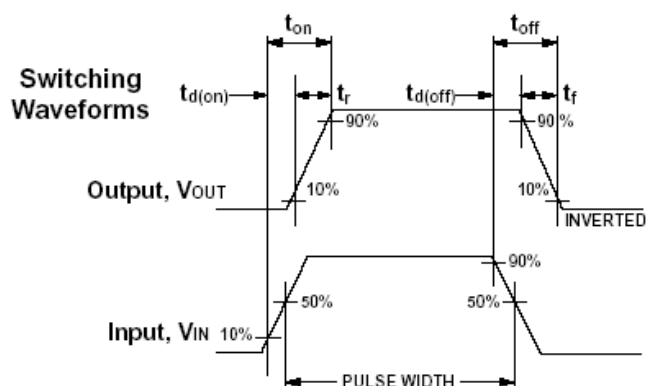
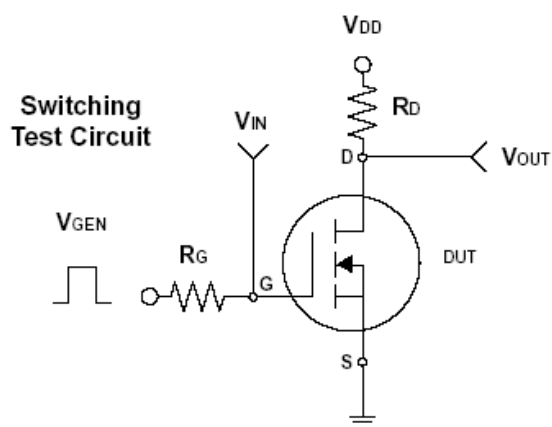
Parameter 极限参数	Symbol 符号	Limit 范围	Unit 单位	
Drain-Source Voltage 漏源电压	$V_{DS}$	30	V	
Gate-Source Voltage 栅源电压	$V_{GS}$	$\pm 20$		
Continuous Drain Current 连续漏极电流	$I_D$	40	A	
Pulsed Drain Current 脉冲漏极电流	$I_{DM}$	120		
Maximum Power Dissipation 最大耗散功率	$P_D$	TA = 25°C	3.5	W
		TA = 75°C	2.1	
Operating Junction and Storage Temperature Range 使用及储存温度	$T_J, T_{stg}$	-55 to 150	°C	
Junction-to-Ambient Thermal Resistance (PCB mounted) 结环热阻	$R_{\theta JA}$	75	°C/W	

 \*The device mounted on 1in<sup>2</sup> FR4 board with 2 oz copper

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**ELECTRICAL CHARACTERISTICS** 一般电气特性

Parameter 参数	符号	Test Condition 测试条件	最小值	典型值	最大值	单位
<b>Static 静态参数</b>						
Drain-Source Breakdown Voltage 漏源击穿电压	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	30			V
Drain-Source On-State Resistance 漏源导通电阻	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 25A$		5.7	6.0	mΩ
Drain-Source On-State Resistance 漏源导通电阻	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 25A$		8.5	10.0	
Gate Threshold Voltage 开启电压	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.3	1.8	3	V
Zero Gate Voltage Drain Current 零栅压漏极电流	$I_{DSS}$	$V_{DS} = 24V, V_{GS} = 0V$			1	uA
Gate Body Leakage 漏极短路时截止栅电流	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
Forward Transconductance 正向跨导	$g_{fs}$	$V_{DS} = 5V, I_D = 30A$		82	—	S
Gate Resistance 栅极电阻	$R_g$	$V_{GS}=0V, V_{DS}=0V, f=1MHz$		0.45	—	Ω
<b>Dynamic 动态参数</b>						
Total Gate Charge 栅极总电荷	$Q_g$	$V_{DS}=15V, V_{GS}=4.5V, I_D=17A$		28.4		nC
Gate-Source Charge 栅-源极电荷	$Q_{gs}$			12.4		
Gate-Drain Charge 栅-漏极电荷	$Q_{gd}$			18.9		
Turn-On Delay Time 导通延迟时间	$t_{d(on)}$	$V_{DD}=15V, R_L=15\Omega, I_D=1A,$ $V_{GEN}=10V, R_G=6\Omega$		22.2		ns
Turn-On Rise Time 导通上升时间	$t_r$			15.3		
Turn-Off Delay Time 关断延迟时间	$t_{d(off)}$			85.1		
Turn-Off Fall Time 关断下降时间	$t_f$			15.6		
Input Capacitance 输入电容	$C_{iss}$	$V_{DS} = 8V, V_{GS} = 0V$ $f = 1.0 MHz$		2390		pF
Output Capacitance 输出电容	$C_{oss}$			356		
Reverse Transfer Capacitance 反向传输电容	$C_{rss}$			310		
<b>Source-Drain Diode 源漏二极管参数</b>						
Max. Diode Forward Current 最大正向电流	$I_S$					A
Diode Forward Voltage 正向电压	$V_{SD}$	$I_S = 1A, V_{GS} = 0V$		0.68		V

Note: Pulse test: pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$  注意: 脉冲测试: 脉冲宽度  $\leq 300\mu s$  死区  $\leq 2\%$



**YGMOS Technology Corp.**
**N-Channel 30-V(D-S) MOSFET**
**Typical Characteristics (T<sub>J</sub> = 25° •Noted)**
